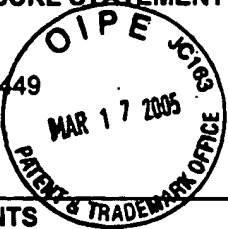


**INFORMATION DISCLOSURE STATEMENT  
BY APPLICANT**

Substitute for form PTO-1449

Sheet 1 of 2



Application Number	09/888,336
Filing Date	22 June 2001
First Named Inventor	Robert E. Dvorak
Art Unit	2163
Examiner Name	Unassigned
Attorney Docket Number	BLFR 1004-1

**U.S. PATENT DOCUMENTS**

Examiner's Initials		Patent No. Number-Kind Code	Pub. Date MM-DD- YYYY	Name	Pages, Cols, Lines of Relevant Passages or Figures
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**OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)**

Examiner's Initials		Include name of the author (in CAPITAL LETTERS), title of article, title of item (book, magazine, journal, serial, symposium, etc), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T
lwd ↓	C1	Ackerman, Jerry, "Looking Back to Fashion's Future", The Boston Globe, 10/07/1998 [retrieved 09/09/04], pages 1-3, retrieved from Google.com and archive.org.	
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	C4	KUMAR, MAHESH, Error-based Clustering and Its Application to Sales Forecasting in Retail Merchandising, September 2003, Massachusetts Institute of Technology.	

Examiner Signature	Beth Van Doren	Date Considered	9/12/05
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<b>Attorney Docket Number</b>	<b>BLFR 1004-1</b>

## U.S. PATENT DOCUMENTS

[illegible]

**OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)**

[illegible]

Examiner Signature	Beth Van Doren	Date Considered	9/12/05
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